

Certified Reference Material

Certificate of Analysis

ISO 17034:2016

ISO/IEC 17025:2017

Revision No.: 000

Revision Date: 01/22/2024



Product ID: IARM-TI52244-22

Product Description: Titanium Alloy, Ti 5-2-2-4-4 / UNS R58650

Description and Intended Use: This Certified Reference Material is covered under the scope of accreditation to ISO 17034 by LGC Standards - Manchester, NH. As an ISO 17034 certified reference material, appropriate use of this material will fulfill the certified reference material and traceability requirements for use in ISO 17025 accredited laboratories. This CRM may come in the form of a solid disk, or chips. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods.

ai meu	10u5.														
				Certified	d Value	s listed i	n wt.%	with ass	ociated	uncerta	inties				
Αl	5.09	± 0.0	5	С	0.008	± 0.0	01	Cr	3.97	± 0.0)9	Н	0.0	07 ±	0.001
Mn	0.0028	± 0.0	005	Мо	4.03	± 0.0)6	N	0.0055	± 0.0	8000	0	0.1	01 ±	0.004
Si	0.026	5 ± 0.003		Sn	Sn 2.01 \pm 0.02 Zr 2.03 \pm 0.02)2								
						Indicati	ve Valı	ues liste	d in ppr	n					
В	6	Co	18	Cu	17	Fe	240	Nb	17	Ni	7	Р	15	Pd	18
Ru	29	S	9	Та	17	V	29	W	13	Υ	2				

Homogeneity and Uncertainty: "Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where N_{prod} is the number of units produced and N_{min} is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity may also be determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculated uncertainty due to inhomogeneity (Unom). Uncertainty of the material is calculated by equation 2, where H=Uhom, S= Standard deviation, t= t-value at 95% CI, and n= number of observations.

1.
$$N_{MIN} = \max(10, \sqrt[3]{N_{PROD}})$$
 2. $U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$

Certification Laboratories: Much of the analytical work performed to assess this material has been carried out by laboratories with proven competence, as indicated by their accreditation to ISO 17025. It is an implicit requirement for this accreditation that analytical work should be performed with due traceability, via an unbroken chain of comparisons, each with stated uncertainty, to primary standards such as the mole, or to nationally- or internationally-recognised reference materials. Of the individual results herein, some have traceability (to the mole) via primary analytical methods. Some are traceable to substances of known stoichiometry. Most have traceability via commercial solutions. Furthermore, some results have additional traceability to NIST standards, as part of the analytical calibration or process control.

- Anderson Laboratories, Inc. Greendale, WI
- Dirats Laboratories Westfield, MA
- EAG Laboratories Liverpool, NY
- Elemental Analysis Inc. Lexington, KY
- IMR Test Labs Lansing, NY
- Laboratory Testing, Inc. Hatfield, PA
- LGC Standards Manchester, NH NSL Analytical Services - Cleveland, OH
- Scrooby's Laboratory Service Pty Ltd Benoni, South Africa
- SGS MSi Melrose Park, IL
- Sheffield Assay Office Sheffield, England
- TEC Eurolab Campogalliano, Italy

Instructions for Use: The test surface is on the opposite side of the labeled surface, which includes the material identification. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams. The material should be stored in a cool, dry location when

Chips are not recommended for gas analysis.

Period of Validity: The certification of this material is valid indefinitely, within the uncertainty specified, provided the material is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the material is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.

Chuck Goudreau, Certifying Officer

22 January 2024 **Certification Date**



The following data represents all pertinent information reported as it applies to the chemical characterization of this material.

	Al	В	С	Co	Cr	Cu	Fe	Н	Mn	Мо	N	Nb	Ni
1	4.944	0.0001	0.0056	0.00002	3.800	0.0009	0.0173	0.0033	0.0019	3.902	0.0041	0.0007	0.0003
2	4.994	0.0003	0.0059	0.0014	3.800	0.0012	0.0190	0.0047	0.0023	3.915	0.0047	0.0011	0.0006
3	5.010	0.0005	0.0061	0.0019	3.884	0.0018	0.0195	0.0062	0.0025	3.940	0.0050	0.0017	0.0008
4	5.044	8000.0	0.0069	0.0027	3.900	0.0022	0.0210	0.0062	0.0026	3.974	0.0051	0.0034	0.0010
5	5.056	0.0011	0.0080	0.0032	3.909	0.0024	0.0220	0.0068	0.0028	3.982	0.0055	<0.0010	0.0010
6	5.070	<.0010	0.0084	<.0010	3.913	<.0010	0.0222	0.0069	0.0028	3.997	0.0060	<0.0020	<.0010
7	5.079	<0.001	0.0090	<0.001	3.938	<.0020	0.0228	0.0077	0.0028	4.000	0.0067	<0.0005	<0.001
8	5.118	<0.005	0.0090	<0.005	3.943	<0.001	0.0234	0.0085	0.0036	4.007	0.0069	<0.005	<0.005
9	5.136	<0.005	0.0111	<0.005	3.946	<0.005	0.0245	0.0087	0.0036	4.039		<0.005	<0.005
10	5.148				4.015	<0.005	0.0255		<0.005	4.040		< 0.02	
11	5.160				4.110		0.0297		<0.005	4.059			
12	5.192				4.199		0.0325			4.154			
13	5.255				4.271		0.0350			4.175			
14										4.290			
Mean	5.093	0.0006	0.0078	0.0018	3.971	0.0017	0.0242	0.0066	0.0028	4.034	0.0055	0.0017	0.0007
STDV	0.086	0.0004	0.0018	0.0012	0.143	0.0006	0.0053	0.0017	0.0006	0.108	0.0010	0.0012	0.0003
Certified	5.09	(0.0006)	0.008	(0.0018)	3.97	(0.0017)	(0.0242)	0.007	0.0028	4.03	0.0055	(0.0017)	(0.0007)
Ucrm	0.05		0.001		0.09			0.001	0.0005	0.06	0.0008		
Methods	I,X,O	I,G	С	I,G	I,X	1,0	I,IM,X,G,O	F	I,IM,G	I,X,O	F	I,G	I,G

	0	Р	Pd	Ru	S	Si	Sn	Та	٧	W	Y	Zr
1	0.0930	0.0002	0.0013	0.0022	0.0002	0.0150	1.956	0.0002	0.0013	0.0002	0.0001	1.981
2	0.0970	0.0013	0.0022	0.0032	0.0010	0.0200	1.977	0.0020	0.0021	0.0017	0.0003	2.001
3	0.0977	0.0014	<0.00001	0.0033	0.0015	0.0210	1.982	0.0030	0.0023	0.0020	0.0003	2.004
4	0.1010	0.0031	<0.0001	<0.00001	<.0010	0.0229	1.993	<0.0005	0.0038	<.0010	<0.0001	2.007
5	0.1012	<0.001	< 0.001	<0.001	<0.0002	0.0260	2.006	<0.0010	0.0039	<0.001	<0.001	2.019
6	0.1030	<0.005	<0.0010	<0.0010	<0.0005	0.0276	2.007	<0.005	0.0040	<0.0010	<0.0010	2.020
7	0.1070	< 0.0050	<0.005	<0.01	<0.001	0.0277	2.008	<0.005	< 0.001	<0.005	<0.005	2.030
8	0.1084		<0.01			0.0280	2.010		<0.001	<0.005	<0.005	2.031
9						0.0283	2.020		<0.005			2.045
10						0.0287	2.031		<0.005			2.052
11						0.0323	2.032					2.074
12						0.0323	2.038					2.080
13							2.113					2.091
14												
Mean	0.1010	0.0015	0.0018	0.0029	0.0009	0.0258	2.013	0.0017	0.0029	0.0013	0.0002	2.033
STDV	0.0052	0.0012	0.0006	0.0006	0.0007	0.0052	0.038	0.0014	0.0011	0.0009	0.0001	0.033
Certified	0.101	(0.0015)	(0.0018)	(0.0029)	(0.0009)	0.026	2.01	(0.0017)	(0.0029)	(0.0013)	(0.0002)	2.03
UCRM	0.004					0.003	0.02					0.02
Methods	F	I,G		1	С	I,IM,G,X,O	I,X,O	1	I,IM,G,O	I,G	1	I,X

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES

